

Product data sheet

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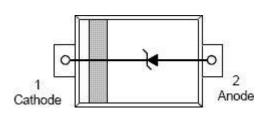
Semiconductor Compiance

Applications

- Cellular phones
- Portable devices
- Digital cameras
- Power supplies

Features

- Small Body Outline Dimensions
- Low Body Height
- Peak Power up to 200 Watts @ 8 x 20 _sPulse
- Low Leakage
- Response Time is Typically < 1 ns
- ESD Rating of Class 3 (> 16 kV) per Human Body Model
- IEC61000-4-2 Level 4 ESD Protection
- IEC61000-4-4 Level 4 EFT Protection
- We declare that the material of product compliance with RoHS requirements.



SOD-523

Device	V _{RWM} (V)	I _R (uA) @ V _{RWM}	V _{BR} (V)@ I _T (Note 1)	Ιτ	Vc (V) @ I _{PP} =5 A*	V _c (V) @ Max I _{PP} *	І _{РР} (А)*	Р _{РК} (W)*	C (pF)
	Max	Мах	Min	mA	Тур	Max	Max	Max	Тур
ESD3V3D5-MS	3.3	1.0	5.0	1.0	8.4	14.1	11.2	158	105
ESD5V0D5-MS	5.0	1.0	6.2	1.0	11.6	18.6	9.4	174	80
ESD7V0D5-MS	7.0	1.0	7.5	1.0	13.5	22.7	8.8	200	65
ESD12VD5-MS	12	1.0	13.5	1.0	25.5	30	5	150	55

Electrical Characteristics Ratings at 25°C ambient temperature unless otherwise specified.VF = 0.9V at IF = 10mA

Absolute Ratings (Tamb=25°C)

Symbol	Parameter	Value	Units
P _{PP}	Peak Pulse Power (t _p = 8/20µs)	200	W
TL	Maximum lead temperature for soldering during 10s	260	°C
T _{stg}	Storage Temperature Range	-55 to +150	°C
T _{op}	Operating Temperature Range	-40 to +125	°C
Tj	Maximum junction temperature	150	°C
	IEC61000-4-2 (ESD) air discharge contact discharge	土15 土8	KV
	IEC61000-4-4 (EFT)	40	А
	ESD Voltage Per Human Body Model	16	KV





Electrical Parameter

G 1 1			
Symbol	Parameter		
I _{PP}	Maximum Reverse Peak Pulse Current		
Vc	Clamping Voltage @ IPP		
V _{RWM}	Working Peak Reverse Voltage		
I _R	Maximum Reverse Leakage Current @ V _{RWM}		
Ι _Τ	Test Current		
V _{BR}	Breakdown Voltage @ I⊤		

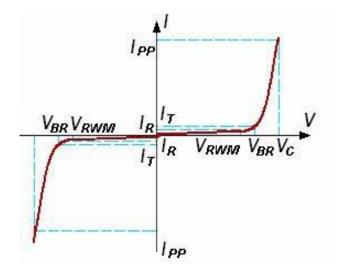
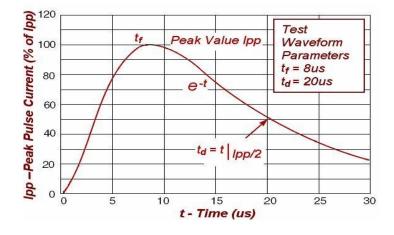
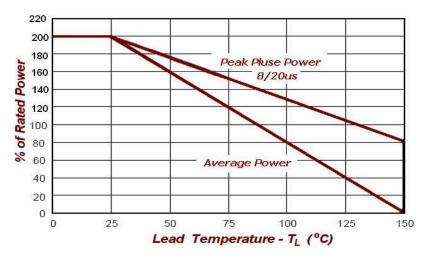


FIG1: Pulse Waveform



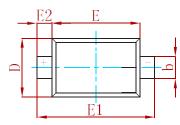


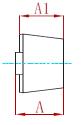


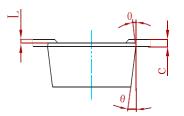




PACKAGE MECHANICAL DATA

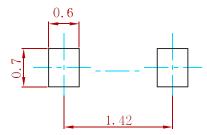






Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	0.510	0.770	0.020	0.031	
A1	0.500	0.700	0.020	0.028	
b	0.250	0.350	0.010	0.014	
С	0.080	0.150	0.003	0.006	
D	0.750	0.850	0.030	0.033	
E	1.100	1.300	0.043	0.051	
E1	1.500	1.700	0.059	0.067	
E2	0.200	REF	0.008 REF		
L	0.010	0.070	0.001	0.003	
0	7° F	REF	7° REF		

Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.

3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
ESDXXXD5-MS	SOD-523	3000





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